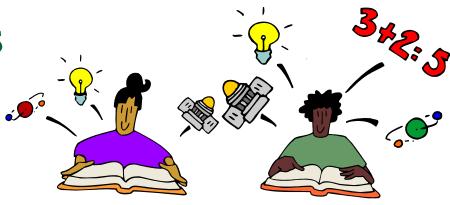


ECEG-2131 (AEI): Carrier Transport and PN junction

Addis Ababa Institute of Technology (AAIT) School of Electrical and Computer Engineering



Learning Outcomes



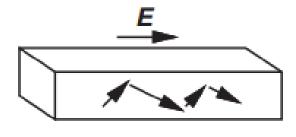
- At the end of the lecture, students should be able to know about:
 - Drift Current.
 - Diffusion Current
 - Resistivity of a material
 - Conductivity of a material
 - The PN junction



Carrier Transport

- Having studied charge carriers and the concept of doping, we are ready to examine the movement of charge in semiconductors, i.e., the mechanisms leading to the flow of current.
- Current = Drift + Diffusion

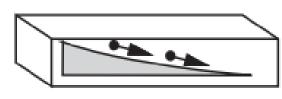
Drift Current



$$J_n = q n \mu_n E$$

$$J_p = q p \mu_p E$$

Diffusion Current



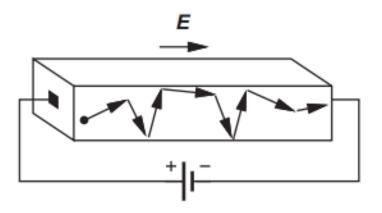
$$J_n = q D_n \frac{dn}{dx}$$

$$J_{\rm p} = -q D_{\rm p} \frac{dp}{dx}$$



Drift

Drift it is the movement of charge carriers due to an electric field.



- Charge carriers are accelerated by the field and accidentally collide with the atoms in the crystal, eventually reaching the other end and flowing into the battery.
- The acceleration due to the field and the collision with the crystal counteract, leading to a constant velocity for the carriers.

Drift

We expect the velocity, v, to be proportional to the electric field strength, E:

$$v \propto E$$
,

$$v = \mu E$$
,

- Where μ is called the "mobility". For example in silicon, the mobility of electrons, $\mu_n = 1350 \text{ cm}^2/(V \cdot s)$, and that of holes, $\mu_p = 480 \text{ cm}^2/(V \cdot s)$.
- For electrons and holes, we can rewrite the formula as follows:

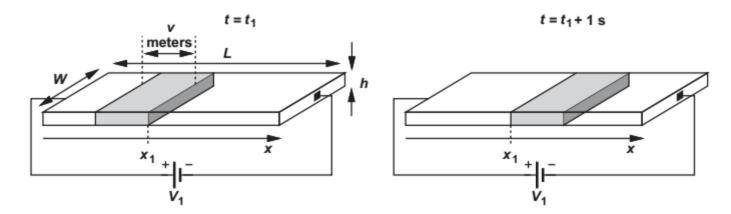
$$\vec{v_e} = -\mu_n \vec{E}.$$

$$\vec{v_h} = \mu_p \vec{E}.$$

So, how can we calculate the current due to drift based on the drift velocity?



Drift



We can calculate the total charge passing through in 1 second as follows,

$$I = -v \cdot W \cdot h \cdot n \cdot q$$

The corresponding current density due to electrons is given by,

$$J_{tot} = \mu_n E \cdot n \cdot q + \mu_p E \cdot p \cdot q$$

$$= q(\mu_n n + \mu_p p)E.$$

The conductivity σ of a semiconductor $\sigma = nq_n\mu_n + pq_p\mu_p$



Exercise

Compute the conductivity of an intrinsic Silicon. Assuming $n = p = n_i$ = 1.5 × 10¹⁶carriers/m³, $\mu_n = 0.14$ m²/(V · s) and $\mu_p = 0.05$ m²/(V · s)

$$\sigma = nq_n\mu_n + pq_p\mu_p$$

$$\sigma = n_i q(\mu_p + \mu_n)$$

$$\sigma = (1.5 \times 10^{16})(1.6 \times 10^{-19})(0.14 + 0.05)$$

$$\sigma = 4.56 \times 10^{-4} S/m$$



Exercise

- A bar of silicon with intrinsic electron density 1.4×10^{16} electrons/m³ is doped with impurity atoms until the hole density is 8.5×10^{21} holes/m³.
- Find the electron density of the extrinsic material

$$n = \frac{n_i^2}{p} = \frac{(1.4 \times 10^{16})^2}{8.5 \times 10^{21}} = 2.3 \times 10^{10} electronss/m^3$$

- Is the extrinsic material n-type or p-type Since p > n, the material is p-type.
- Find the extrinsic conductivity

$$\sigma = nq_n\mu_n + pq_p\mu_p$$

$$\sigma = (2.3 \times 10^{10})(0.14)(1.6 \times 10^{-19}) + (8.5 \times 10^{21})(0..05)(1.6 \times 10^{-19})$$

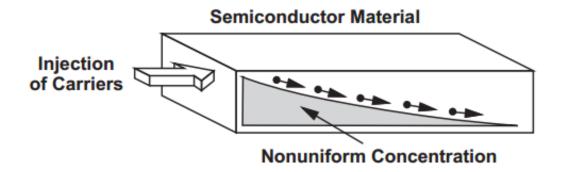
$$\sigma = 5.152 \times 10^{-10} + 68 \approx 68S/m$$



Diffusion

- In addition to drift, another mechanism can lead to current flow.
- If charge carriers are "dropped" (injected) into a semiconductor it creates a nonuniform density of charge carriers.
- This high concentration of the injected carriers tend to flow from the region of high concentration to regions of low concentration.
- This mechanism is known as "diffusion".
- Even in the absence of an electric field, the carriers move toward regions of low concentration, thereby carrying an electric current so long as the nonuniformity is sustained.

Diffusion



 From what we know qualitatively, the more nonuniform the concentration the more the current. Hence,

$$I \propto \frac{dn}{dx}$$

 We call dn/dx the concentration gradient with respect to x. If each carrier has a charge equal to q and the semiconductor has a cross sectional area of A,

$$I \propto Aq \frac{dn}{dx}$$
.

Diffusion

Therefore the total current will be given by,

$$I = AqD_n \frac{dn}{dx},$$

- Where D_n is a proportionality factor called the "diffusion constant".
- In intrinsic Silicon, $D_n = 34 \text{cm}^2/\text{s}$ (for electrons), and $D_p = 12 \text{cm}^2/\text{s}$ (for holes).
- The corresponding current density then becomes:

$$J_n = qD_n \frac{dn}{dx}. \qquad J_p = -qD_p \frac{dp}{dx}.$$

$$J_{tot} = q \left(D_n \frac{dn}{dx} - D_p \frac{dp}{dx} \right).$$

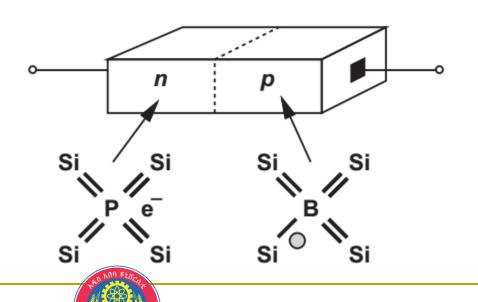
Einstein Relation

- From our discussions, we have seen two types of currents of a semiconductor.
- These have introduced factors μ_n (or μ_p) and D_n (or D_p) for drift and diffusion respectively.
- They can be related using the Einstein relation,

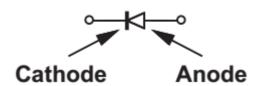
$$\frac{D}{\mu} = \frac{kT}{q}$$

pn Junction

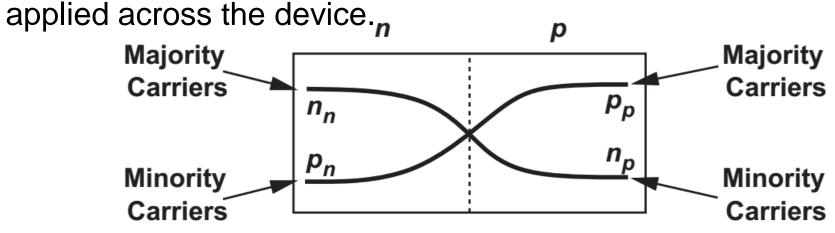
- An interesting situation arises when we introduce n-type and p-type dopants into two adjacent sections of a piece of semiconductor.
- We can only build this device on a single crystal, i.e. we can't bring a separate n-type material and p-type material together.
- This device finds applications in many electronic devices



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With no external connections, i.e. the terminals are open and no voltage is



 n_n : Concentration of electrons on n side

 p_n : Concentration of holes on n side

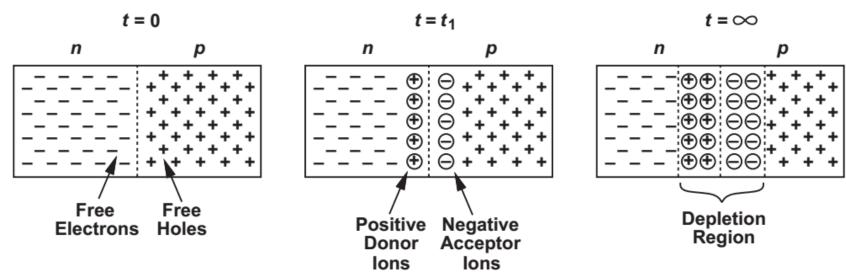
 p_p : Concentration of holes on p side

 n_p : Concentration of electrons on p side

There is an initial diffusion of majority carriers from both sides.

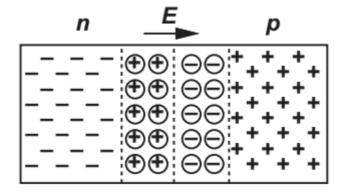


Initially there is a diffusion of carriers from both sides.



- This diffusion eventually decays to zero.
- For every electron that departs from the n side, a positive ion is left behind.
- The immediate vicinity of the junction is depleted of free carriers and hence called the "depletion region".

- Because of the ions left in the depletion region, an electric field is generated.
- Hence, we have a drift current which opposes the diffusion current.



 The junction reaches equilibrium once the electric field is strong enough to completely stop the diffusion current.

In equilibrium, we must impose this condition,

$$|I_{\text{drift},p}| = |I_{\text{diff},p}|$$

From this, we get:

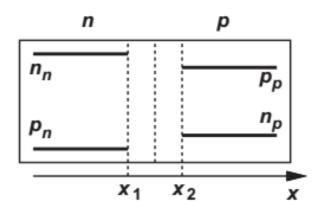
$$|I_{\text{drift},n}| = |I_{\text{diff},n}|.$$

$$q\mu_p pE = qD_p \frac{dp}{dx}$$

Finally,

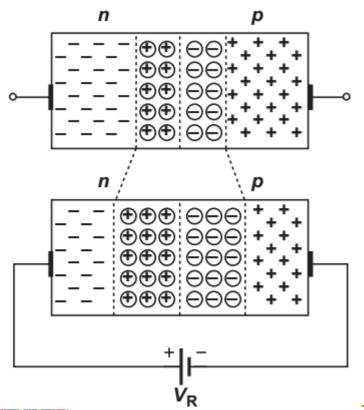
$$V(x_2) - V(x_1) = -\frac{D_p}{\mu_p} \ln \frac{p_p}{p_n}.$$

$$|V_0| = \frac{kT}{q} \ln \frac{p_p}{p_n} \qquad \text{Of} \qquad V_0 = \frac{kT}{q} \ln \frac{N_A N_D}{n_z^2}$$

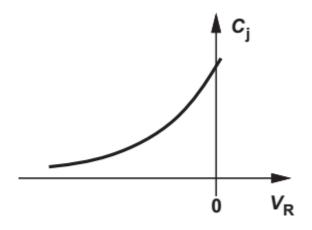


pn junction under reverse bias

 We first apply a voltage source that makes the n side more positive and the p side more negative, i.e. reverse bias

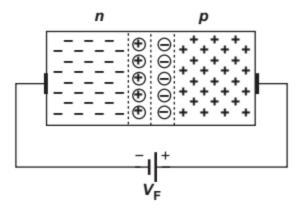


$$C_j = \frac{C_{j0}}{\sqrt{1 - \frac{V_R}{V_0}}}$$



pn junction under forward bias

 We can also apply a voltage that makes the p side more positive and the n side more negative, i.e. forward bias



This is also known as the diode.

What to Do This Week?

- Reading Assignment
 - Diode modeling
 - Diode circuits
 - Diode applications